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(12) **United States Design Patent** (10) **Patent No.:** **US D922,546 S**
Yoshida et al. (45) **Date of Patent:** **** Jun. 15, 2021**

(54) **COMPOSITE SEAL MEMBER FOR SEMICONDUCTOR PRODUCTION APPARATUS**

CPC F16K 51/02; F16J 15/025; F16J 15/0887; F16J 15/104; F16J 15/128
See application file for complete search history.

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(73) Assignee: **Valqua, Ltd.**, Tokyo (JP)

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(**) Term: **15 Years**

(Continued)

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Related U.S. Application Data

CN	303747329 S	7/2016
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(Continued)

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(30) **Foreign Application Priority Data**

(57) **CLAIM**

The ornamental design for a composite seal member for semiconductor production apparatus, as shown and described.

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Feb. 8, 2018 (JP)	2018002528

DESCRIPTION

(51) **LOC (13) Cl.** **23-01**
(52) **U.S. Cl.**
USPC **D23/269**
CPC **F16J 15/025** (2013.01)

FIG. 1 is a perspective view of a composite seal member for semiconductor production apparatus, showing our new design;
FIG. 2 is a front elevation view thereof;
FIG. 3 is a rear elevation view thereof;
FIG. 4 is a left side elevation view thereof;
FIG. 5 is a right side elevation view thereof;
FIG. 6 is a top view thereof;
FIG. 7 is a bottom view thereof;
FIG. 8 is a cross-sectional view thereof; and,

(58) **Field of Classification Search**
USPC D15/7, 9, 11, 17, 21, 28, 123, 199;
D23/269, 386, 259; D8/349;
277/602-626; 285/95, 109, 336, 910, 918

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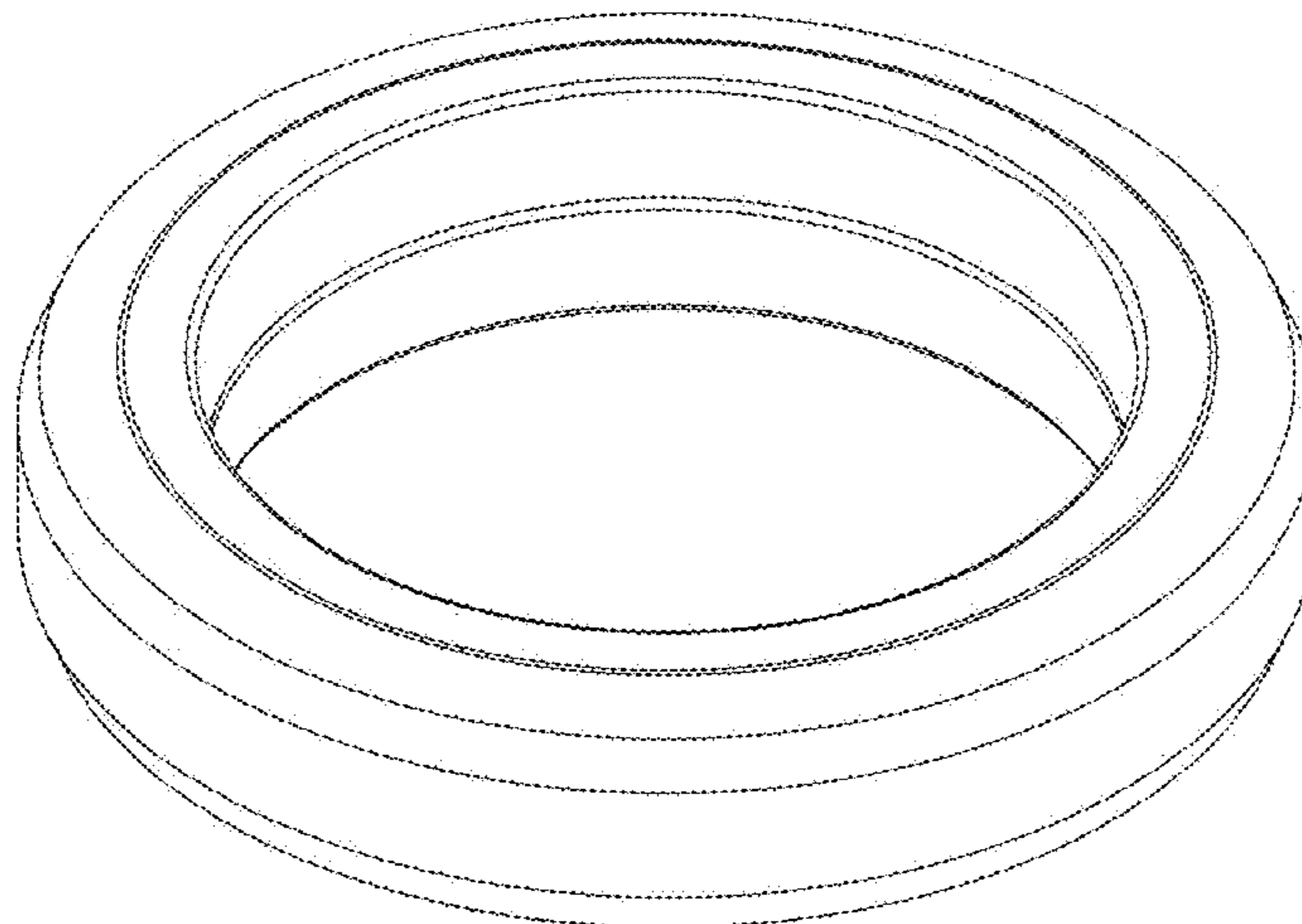


FIG. 9 is an enlarged cross-sectional view of a portion thereof.

1 Claim, 9 Drawing Sheets

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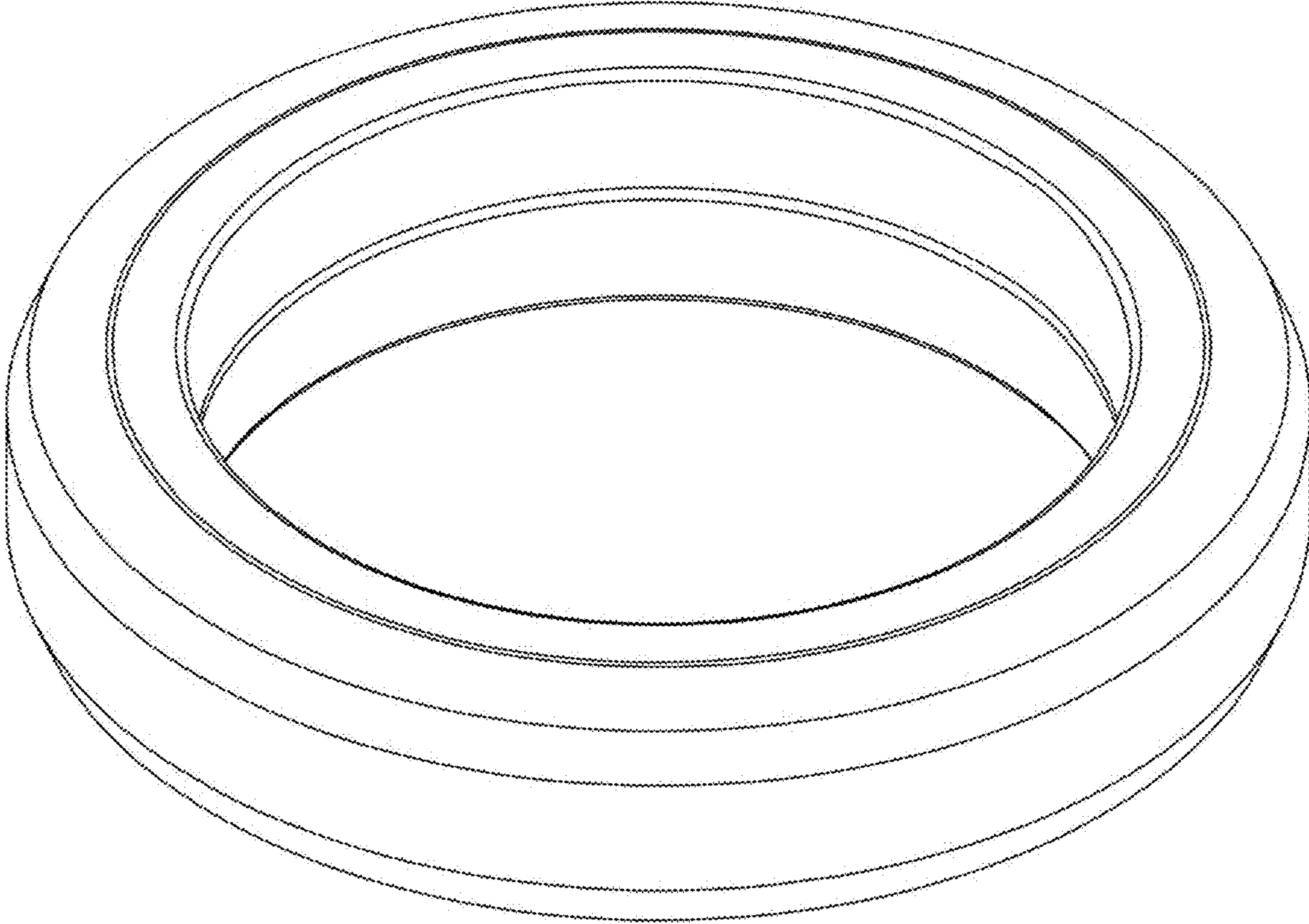


FIG. 1

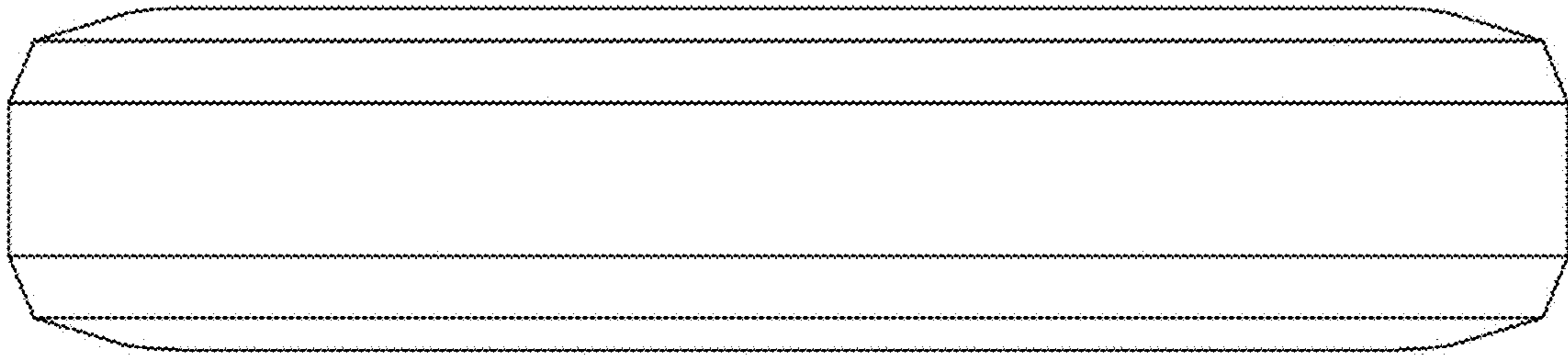


FIG. 2

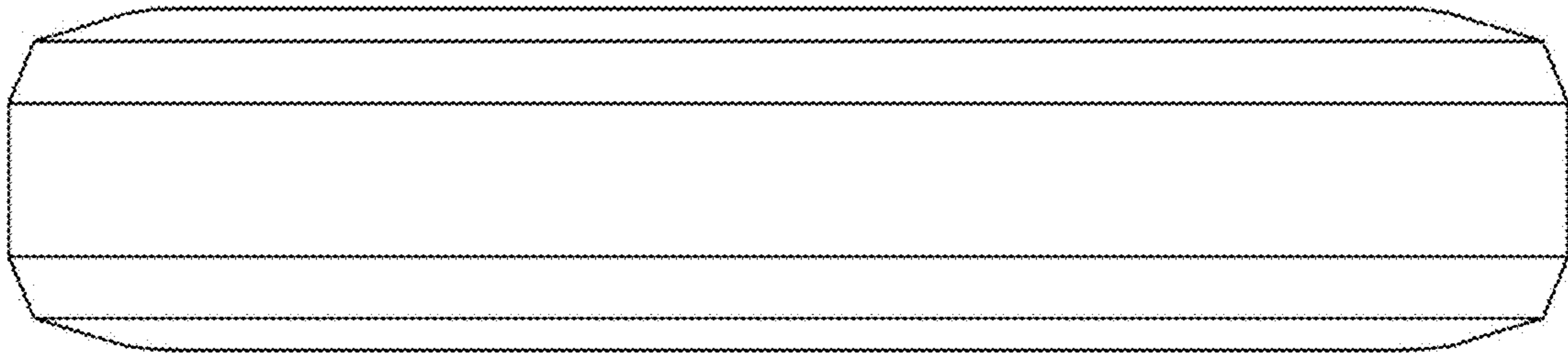


FIG. 3

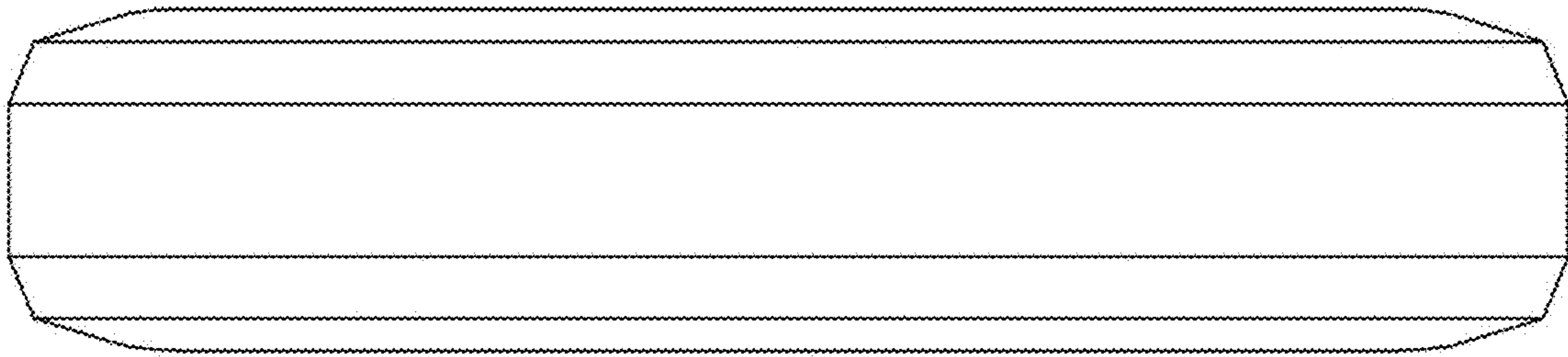


FIG. 4

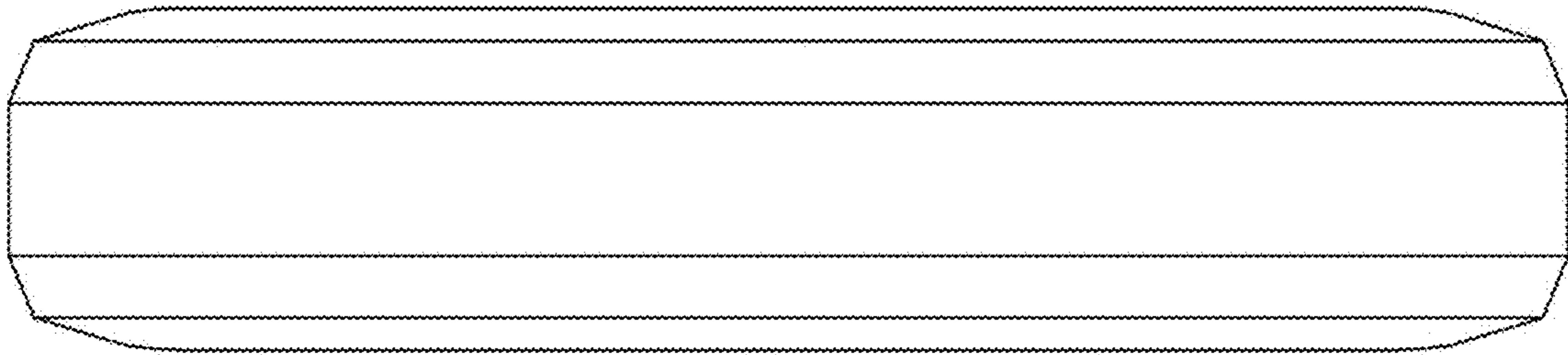


FIG. 5

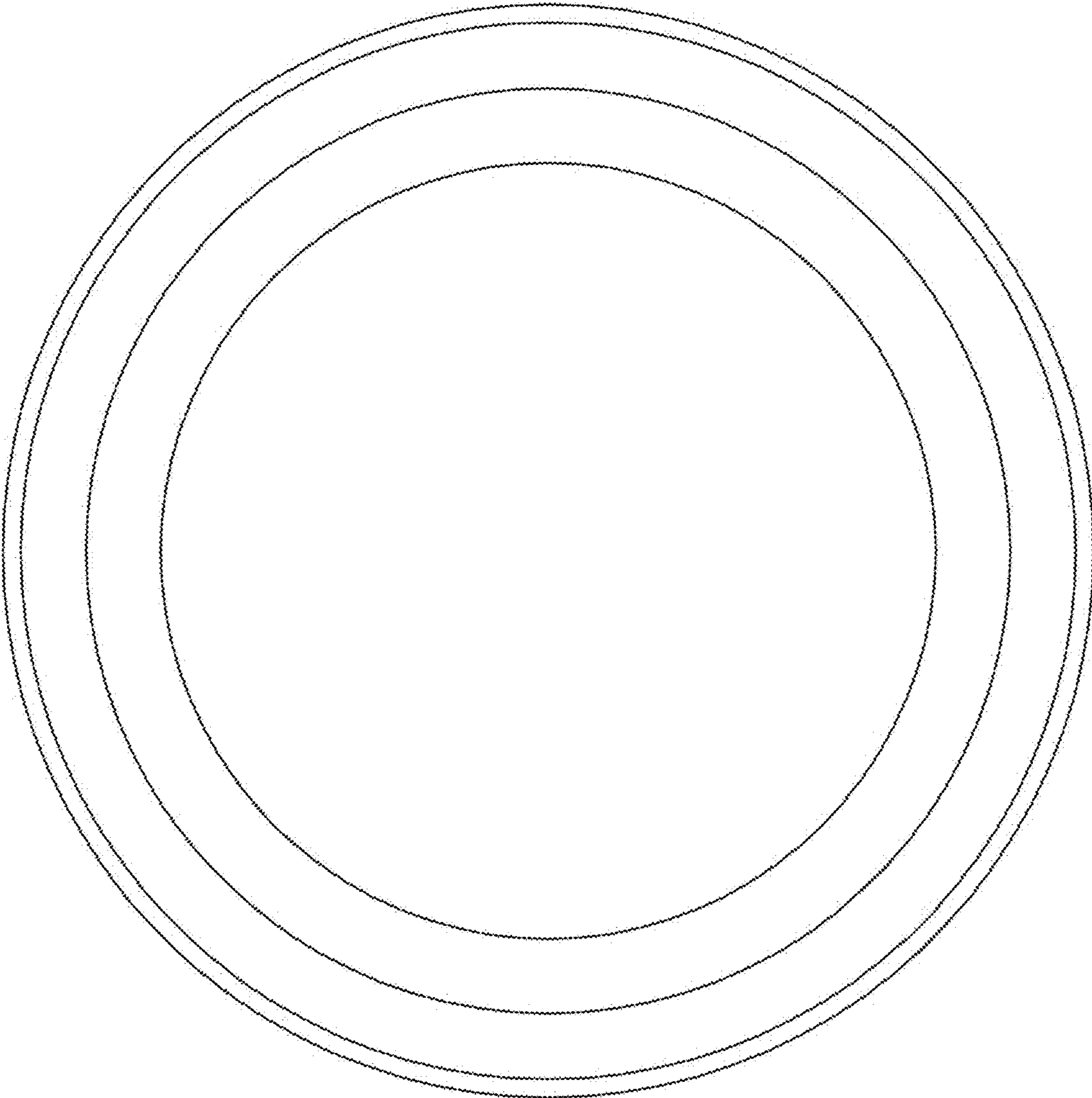


FIG. 6

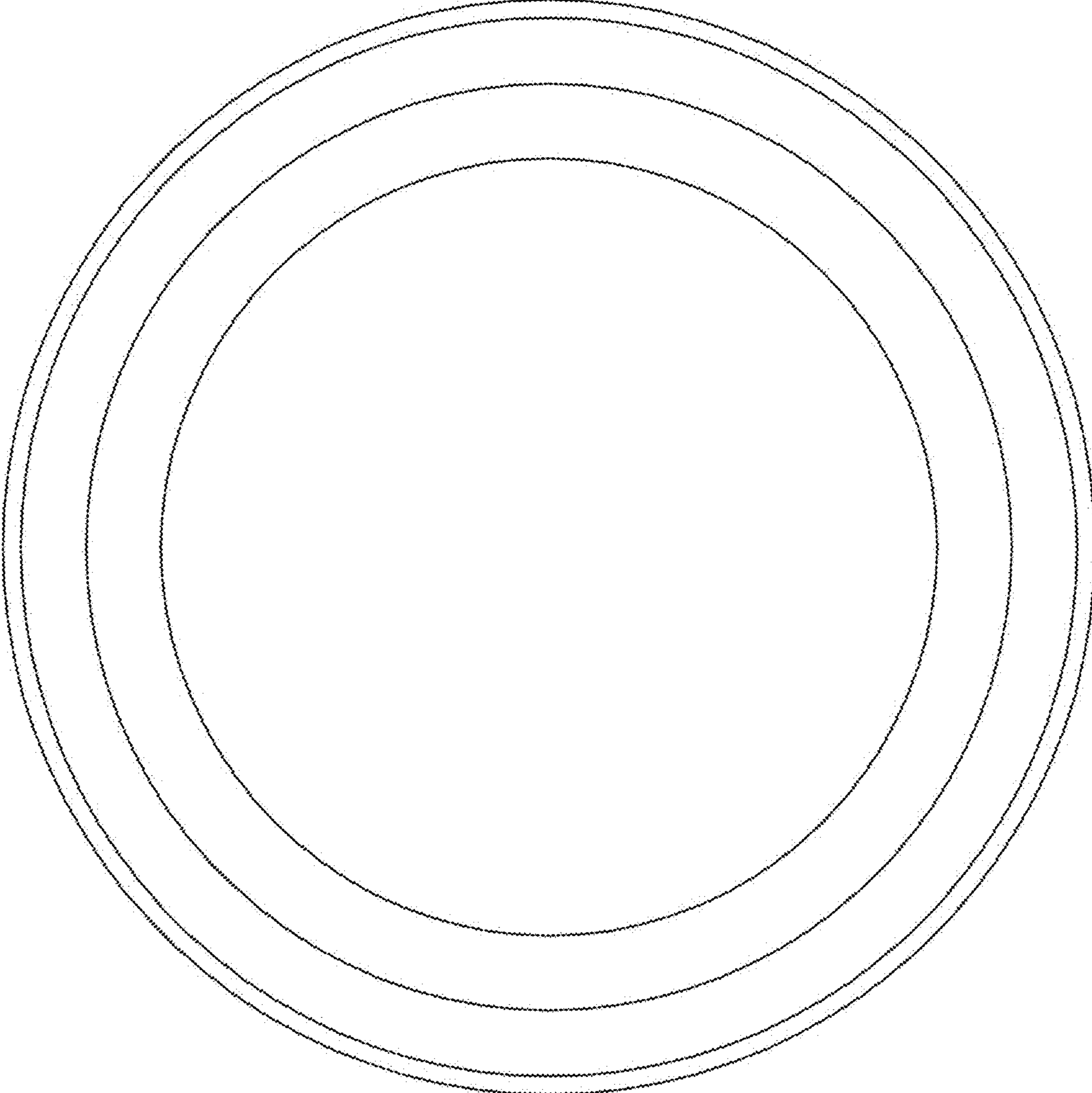


FIG. 7

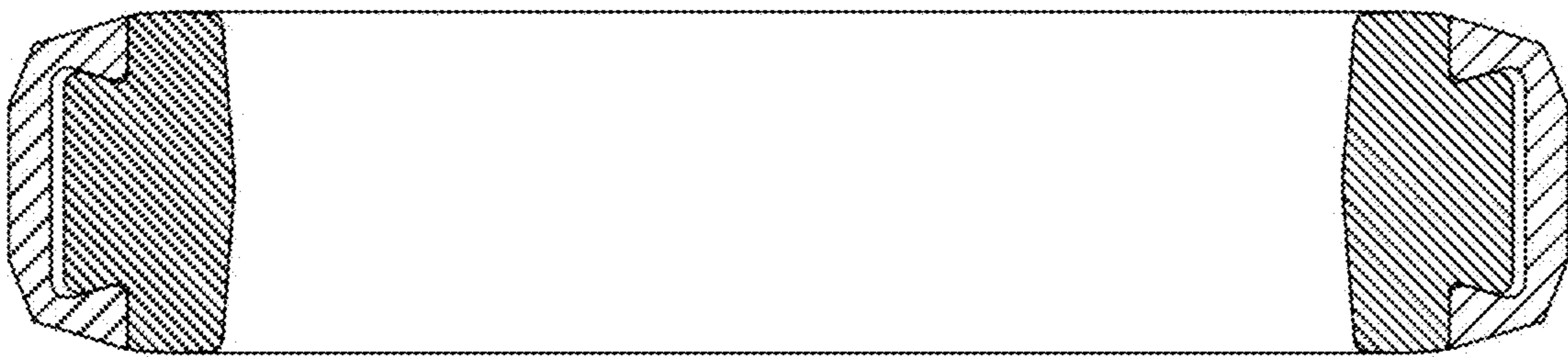


FIG. 8

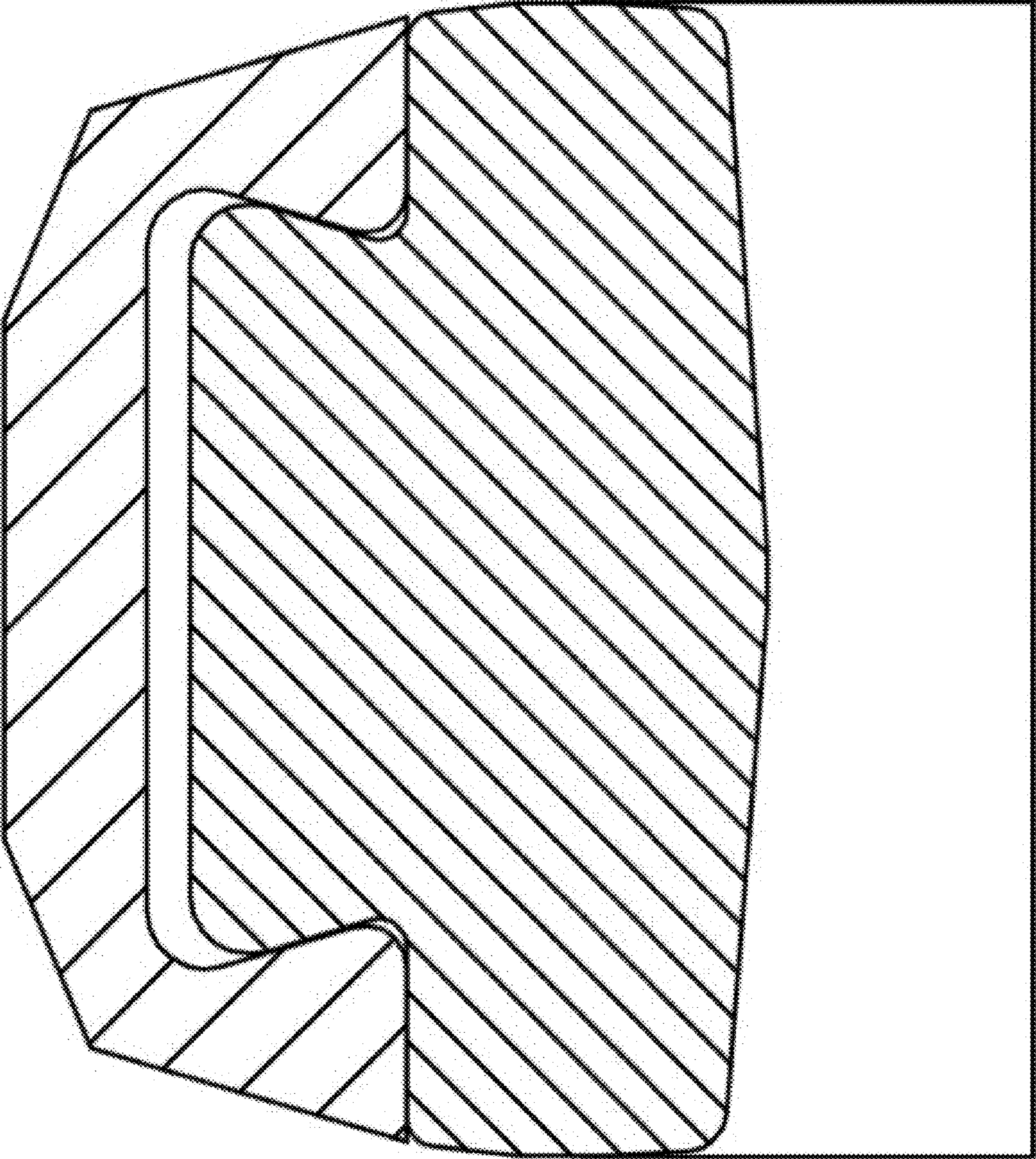


FIG. 9